

Application/Control No.	ol No. Applicant(s)/Patent under Reexamination	
09/879,575	REEDS ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

SEARCHED					
Class	Subclass	Date	Examiner		
380	37	10/17/2007	ET		
380	43	10/17/2007	ET		
380	247	10/17/2007	ET _.		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	10/17/2007	ET		
NPL - GOOGLE, IEEE XPOLORE	10/17/2007	ΕT		
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	10/17/2007	ĒΤ		